SCBS142M - MAY 1992 - REVISED MARCH 2000

<ul> <li>Members of the Texas Instruments Widebus™ Family</li> <li>State of the Art Advanced BiGMOS</li> </ul>	SN74LVTH16244B DG	A WD PACKAGE GG, DGV, OR DL PACKAGE VIEW)
<ul> <li>State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power</li> </ul>	1 OE [ 1 1 Y1 [ 2	48 20E 47 1A1
<ul> <li>Dissipation</li> <li>Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With</li> </ul>	1Y2 [] 3 GND [] 4 1Y3 [] 5	46   1A2 45   GND 44   1A3
<ul> <li>3.3-V V<sub>CC</sub>)</li> <li>Support Unregulated Battery Operation</li> </ul>	1Y4 🕻 6	43 1A3 43 1A4 42 V <sub>CC</sub>
Down to 2.7 V	V <sub>CC</sub> [ 7 2Y1 [ 8	41 2A1
<ul> <li>Typical V<sub>OLP</sub> (Output Ground Bounce)</li> <li>&lt;0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C</li> </ul>	2Y2 9 GND 10	39 GND
<ul> <li>I<sub>off</sub> and Power-Up 3-State Support Hot Insertion</li> </ul>	2Y3 11 2Y4 12	37 2A4
<ul> <li>Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown</li> </ul>	3Y1 [ 13 3Y2 [ 14 GND [ 15	35 3A2
<ul><li>Resistors</li><li>Latch-Up Performance Exceeds 100 mA Per</li></ul>	3Y3 [ 16 3Y4 [ 17	33 <b>3</b> A3
<ul> <li>JESD 78, Class II</li> <li>ESD Protection Exceeds JESD 22</li> </ul>	V <sub>CC</sub> [ 18 4Y1 [ 19	31 🛛 V <sub>CC</sub>
<ul> <li>2000-V Human-Body Model (A114-A)</li> <li>200-V Machine Model (A115-A)</li> </ul>	4Y2 20 GND 21	29 4A2
<ul> <li>– 1000-V Charged-Device Model (C101)</li> <li>Package Options Include Plastic Shrink</li> </ul>	4Y3 [ 22 4Y4 [ 23	27 <b>4</b> A3
Small-Outline (DL), Thin Shrink	4 <del>0E</del> [ 24	25 30E

Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

## description

The SN54LVTH16244A and SN74LVTH16244B devices are 16-bit buffers and line drivers designed for low-voltage (3.3-V)  $V_{CC}$  operation, but with the capability to provide a TTL interface to a 5-V system environment. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical active-low output-enable ( $\overline{OE}$ ) inputs.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When  $V_{CC}$  is between 0 and 1.5-V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5-V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

These devices are fully specified for hot-insertion applications using I<sub>off</sub> and power-up 3-state. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Widebus is a trademark of Texas Instruments.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



Copyright © 2000, Texas Instruments Incorporated On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

SCBS142M - MAY 1992 - REVISED MARCH 2000

## description (continued)

The SN54LVTH16244A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LVTH16244B is characterized for operation from -40°C to 85°C.

**FUNCTION TABLE** (each 4-bit buffer)

INP	UTS	OUTPUT							
OE	Α	Y							
L	Н	Н							
L	L	L							
Н	Х	Z							

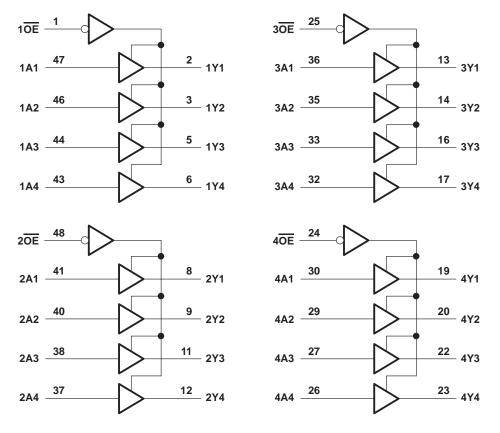
logic symbol<sup>†</sup>

10E 20E 30E 40E	1 48 25 24 24	EN1 EN2 EN3 EN4				
1A1	47		1		2	1Y1
1A2	46			1 V	3	1Y2
1A3	44				5	1Y3
1A3	43				6	1Y4
2A1	41		1	2 ▽	8	2Y1
2A1 2A2	40		1	2 *	9	211 2Y2
2A2 2A3	38				11	2Y3
2A3 2A4	37	<u> </u>			12	213 2Y4
2A4 3A1	36		4	3 ▽	13	
3A2	35	<u> </u>	1	3 V	14	3Y1
	33	<u> </u>			16	3Y2
3A3	32	┣───			17	3Y3
3A4	30	┣──	4	4 ▽	19	3Y4
4A1	29		1	4 ∨	20	4Y1
4A2	27				22	4Y2
4A3	26	<b> </b>			23	4Y3
4A4						4Y4

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



## logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance	
or power-off state, V <sub>O</sub> (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state, V <sub>O</sub> (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Current into any output in the low state, I <sub>O</sub> : SN54LVTH16244A	
SN74LVTH16244B	
Current into any output in the high state, I <sub>O</sub> (see Note 2): SN54LVTH16244A	48 mA
SN74LVTH16244B	64 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–50 mA
Output clamp current, $I_{OK}$ (V <sub>O</sub> < 0)	
Package thermal impedance, $\theta_{IA}$ (see Note 3): DGG package	
DGV package	
DL package	
Storage temperature range, T <sub>stg</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .

3. The package thermal impedance is calculated in accordance with JESD 51.



SCBS142M - MAY 1992 - REVISED MARCH 2000

## recommended operating conditions (see Note 4)

			SN54LVTH	16244A	SN74LVTH	UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	2.7	3.6	2.7	3.6	V	
VIH	High-level input voltage	2		2		V	
VIL	Low-level input voltage		0.8		0.8	V	
VI	Input voltage		5.5		5.5	V	
ЮН	High-level output current			-24		-32	mA
IOL	Low-level output current			48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
Δt/ΔV <sub>CC</sub>	Power-up ramp rate		200		200		μs/V
ТА	Operating free-air temperature	-55	125	-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



SCBS142M - MAY 1992 - REVISED MARCH 2000

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			SN54LVTH16244A			SN74LVTH16244B				
FAI	RAINETER				түр†	MAX	MIN	түр†	MAX	UNIT		
V <sub>IK</sub> V <sub>CC</sub> = 2.7 V, I <sub>I</sub>			lj = -18 mA			-1.2			-1.2	V		
		$V_{CC} = 2.7 V \text{ to } 3.6 V,$	I <sub>OH</sub> = -100 μA	V <sub>CC</sub> –0.	.2		V <sub>CC</sub> -0.	2				
Varia		V <sub>CC</sub> = 2.7 V,	I <sub>OH</sub> = -8 mA	2.4			2.4			v		
VOH		V <sub>CC</sub> = 3 V	I <sub>OH</sub> = -24 mA	2								
		vCC = 2 v	I <sub>OH</sub> = -32 mA				2					
		Vec - 27V	I <sub>OL</sub> = 100 μA			0.2			0.2			
		$V_{CC} = 2.7 V$	I <sub>OL</sub> = 24 mA			0.5			0.5			
Max			I <sub>OL</sub> = 16 mA			0.4			0.4	v		
VOL			I <sub>OL</sub> = 32 mA			0.5			0.5	V		
		$V_{CC} = 3 V$	I <sub>OL</sub> = 48 mA			0.55						
			I <sub>OL</sub> = 64 mA						0.55			
		V <sub>CC</sub> = 0 or 3.6 V,	V <sub>I</sub> = 5.5 V			50			10			
	Control inputs	V <sub>CC</sub> = 3.6 V,	$V_I = V_{CC} \text{ or } GND$			±1			±1	1		
II	Data inputs	V <sub>CC</sub> = 3.6 V	Al = ACC			1			1	μA		
			V <sub>I</sub> = 0			-5			-5			
loff		$V_{CC} = 0,$	$V_{I}$ or $V_{O}$ = 0 to 4.5 V	= 0 to 4.5 V ±100		±100	μΑ					
		V <sub>CC</sub> = 3 V	V <sub>I</sub> = 0.8 V	75			75			μΑ		
ll(hold)	Data inputs		V <sub>I</sub> = 2 V	-75			-75					
. ,		V <sub>CC</sub> = 3.6 V <sup>‡</sup> ,	V <sub>I</sub> = 0 to 3.6 V						±500			
IOZH		V <sub>CC</sub> = 3.6 V,	V <sub>O</sub> = 3 V			5			5	μA		
IOZL		V <sub>CC</sub> = 3.6 V,	$V_{O} = 0.5 V$			-5			-5	μA		
IOZPU		$\frac{V_{CC}}{OE} = 0$ to 1.5 V, V <sub>O</sub> = OE = don't care	= 0.5 V to 3 V,			±100*			±100	μΑ		
IOZPD		$\frac{V_{CC}}{OE}$ = 1.5 V to 0, V <sub>O</sub> = OE = don't care	= 0.5 V to 3 V,			±100*			±100	μA		
		V <sub>CC</sub> = 3.6 V,	Outputs high			0.19			0.19			
ICC		$I_{O} = 0,$	Outputs low		5		5		mA			
		$V_I = V_{CC}$ or GND	Outputs disabled			0.19			0.19	19		
$\Delta I_{CC}$ $V_{CC} = 3 V \text{ to } 3.6 V, \text{ One i}$ Other inputs at $V_{CC}$ or G					0.2			0.2	mA			
Ci		VI = 3 V or 0			4			4		pF		
Co		V <sub>O</sub> = 3 V or 0			9			9		pF		

\*On products compliant to MIL-PRF-38535, this parameter is not production tested.

<sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ . <sup>‡</sup> This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.



## SN54LVTH16244A, SN74LVTH16244B 3.3-V ABT 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS SCBS142M - MAY 1992 - REVISED MARCH 2000

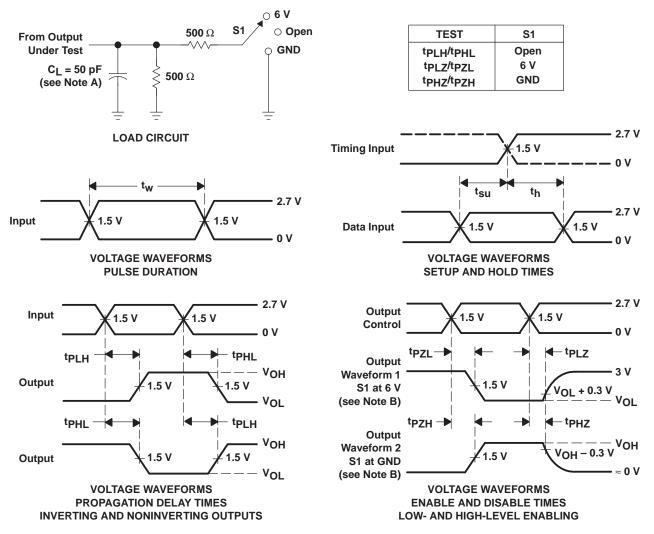
# switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

			S	SN54LVTH16244A			SN74LVTH16244B					
PARAMETER FROM (INPUT)		FROM TO (INPUT) (OUTPUT)		V <sub>CC</sub> = 3.3 V ± 0.3 V V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V			V <sub>CC</sub> = 2.7 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN	MAX	
<sup>t</sup> PLH	А	v	1.1	4.4		4.6	1.2	2.3	3.2		3.7	ns
<sup>t</sup> PHL	~	I	1.1	3.6		3.9	1.2	2	3.2		3.7	7
<sup>t</sup> PZH	ŌĒ	v	1.1	4.6		5.4	1.2	2.6	4		5	ns
tPZL		Ι	1.1	5.4		6.2	1.2	2.7	4		5	115
<sup>t</sup> PHZ	OE	V	1.6	5.7		6.2	2.2	3.3	4.5		5	ns
tPLZ	UE	1	1.2	5		4.7	2	3.1	4.2		4.4	115
<sup>t</sup> sk(o)									0.5			ns

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.



SCBS142M - MAY 1992 - REVISED MARCH 2000



## PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

#### Figure 1. Load Circuit and Voltage Waveforms



#### **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgment, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Customers are responsible for their applications using TI components.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 2000, Texas Instruments Incorporated